

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings of claims in the application:

Listing of Claims:

Claims 1-17. (Canceled)

18. (Currently Amended) A method of classifying defects, comprising the steps of:

determining a sampling rate of defects to be reviewed by a second inspection machine, operable to detect images of defects to be reviewed with a first image magnification, among defects detected by a first inspection machine, operable to detect images of the defects with a second image magnification, the second image magnification being lower than the first image magnification; [[and]]

reviewing, with said second inspection machine, defects sampled from said defects detected by said first inspection machine in accordance with said determined sampling rate; and

classifying, with said second inspection machine, said reviewed defects with a second defect classifier corresponding to said second inspection machine, the reviewed defects being captured with the higher first image magnification;

wherein in the step of determining, said sampling rate is determined for each defect class classified by a first defect classifier corresponding to said first inspection machine to reduce a number of defects to be reviewed by the second inspection machine among the defects detected by the first inspection machine.

19. (Original) The method according to claim 18, wherein said second defect classifier has a decision tree for hierarchically expanding defect classification class elements via branch elements, and wherein said decision tree is such that a classification rule created with

sample inspection information that has been previously derived from an inspection of an inspection sample is individually set for each of said branch elements.

20. (Previously Presented) The method according to claim 19, wherein said individual classification rule that is set for each of said branch elements in said second defect classifier is set on a screen that displays said sample inspection information derived from said inspection of said inspection sample.

21. (Previously Presented) A method according to claim 18, wherein in the step of determining, said sampling rate is determined for each defect class in accordance with a reliability of each defect class classified with said first defect classifier.

Claims 22-23. (Canceled)